

Application/Control No.	Applicant(s)/Patent unde Reexamination	Applicant(s)/Patent under Reexamination	
10/583,743	HAYAKAWA ET AL.		
Examiner	Art Unit		
Vivian Chen	1773		

SEARCHED				
Class	Subclass	Date	Examiner	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH (INCLUDING SEAR		<b>(</b> )
	DATE	EXMR
EAST text search printout	6/22/2007	/VC/
inventor search	6/22/2007	NCI
EAST text search printout	6/25/2007	/VC/